

The logo for NIST (National Institute of Standards and Technology) in black, bold, sans-serif font.The logo for PTB (Physikalisch-Technische Bundesanstalt) in blue, bold, sans-serif font.The logo for EXSA (European X-ray Society) with 'EX' in green and 'SA' in black, all in a sans-serif font.

International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Dissemination of information on the 2010 and 2011 workshops (LNE & NIST)**
- **Presentation of expert groups and road map documents**
- **Industrial and other FP project activities**
- **Implementation of new expert group structure**
- **Continuation of a joint project and follow-up activities**



International initiative on x-ray fundamental parameters

Motivation

- Parameters useful for quantitative x-ray analysis

Strong demand of users from many application fields :
innovative materials, archaeometry, environment, chemistry, etc.

Tables – reliability – uncertainties ?

Lack of recent experimental values (few measurements performed >30 years ago)

- Improvement of experimental facilities

Synchrotron, high resolution detectors, improved electronics
Improvement of calculation speed

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International initiative on x-ray fundamental parameters

Motivation

- **Initiate new measurements taking advantage of technical improvements**
- **Perform similar measurements in different institutes to establish reliability and associated uncertainties of the experimental values**
- **Perform calculation for selected cases (use calculations for interpolations)**
- **Compare calculation to experiment**
- **Provide reliable practical tables to users**

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International initiative on x-ray fundamental parameters

Participants and events

- **Active participation from :**
 - 3 National metrology institutes**
 - 14 Research institutes**
 - 10 Industrial companies**
- **4 international workshops**



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Dissemination of information on previous workshops and events

| | | |
|---------------------------------|-----------|-----------------------------------|
| 1 st workshop Paris | Oct. 2008 | → definition of expert groups |
| 2 nd workshop Berlin | May 2009 | → road map generation |
| Session at EXRS conf. | Jun. 2010 | → scientific community |
| 3 rd workshop Paris | Nov. 2010 | → project options |
| 4 th workshop NIST | July 2011 | → definition of new expert groups |
| prior to EXRS2012 | June 2012 | → FP roadmap document online |



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Presentation of expert groups and road map documents**
 1. **Prioritization of FP requirements (energies, elements, uncertainties)**
 2. **Experimental facilities (needs for improved instrumentation)**
 3. **Theory & codes – challenges: competent use and update of software**
 4. **Compilations (need for new strategies), data processing**
 5. **Definition of technical terms (NMIs: LNE, NIST and PTB)**
 6. **Establishment of a common data base accessible to the public**



International initiative on x-ray fundamental parameters

FP roadmap document

Compilation from the work of 6 EG (Roadmap or other shape)

Introduction

EG1: Priorities from the users point of view

EG2: List of available experimental facilities for new experiments

EG3: Theoretical calculations

EG4: Document on the status of databases (publication)

EG5: Technical document : definitions + translations

EG6: Dissemination of the database



International initiative on x-ray fundamental parameters

FP roadmap document

Please find the first version of the FP roadmap document at either the **EXSA website** at http://exsa.pytalhost.net/news/?attachment_id=375 or at the **LNE-LNHB website** at <http://www.nucleide.org/IIFP.htm>

Access to the FP initiative board

The special password protected area can be found at

<http://exsa.pytalhost.net/FP-XRF/>

with username: **xxx** and password: **xxx**

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International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Industrial FP priorities and project activities (“Fribourg group”)**
 - priorities based on input by industrial manufacturers
 - status of industrial FP projects
- **Extension of competences (input from new attendees)**
 - new ideas, requirements and contributions
- **Continuation of a joint project and contributions by regional projects**
 - discussion and follow-up activities (road map updates, etc.)



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Dissemination of information on the 2010 workshop at LNE, Paris, France
1 day (November 29, 2010)

Morning session:

Welcome (*M.-C. Lépy*)

Summary of the second workshop in Berlin (*B. Beckhoff*)

Objectives of 3rd workshop (*M.-C. Lépy*)

Burkhard Beckhoff (PTB) “Advanced material characterization and nanotechnology: a novel need for improved fundamental parameters”

Y. Ménesguen (LNE) “ Examples of measurements of some FP ”

Statement of needs & competences from new attendees



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Dissemination of information on the 2010 workshop at LNE, Paris, France
1 day (November 29, 2010)

Afternoon session:

Tibor Papp “Specific challenges for FP determination”

Report of expert groups and discussion

Continuing a common project *B. Beckhoff*

Discussion and wish to start a concrete action

Follow-up activities of the FP initiative *T. Jach*

Extension towards USA and Japan



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Dissemination of information on the 2011 workshop at NIST, Gaithersb., US

Day 1 (July 28, 2011) Morning Session

- Welcome (Terrence Jach)
- Introductory Remarks (Michael Mantler), History of Workshop
- Tim Elam, “History of the Elam Absorption Database”
- Eric Gullikson, “The CXRO database and Fundamental Parameter Work”



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Dissemination of information on the 2011 workshop at NIST, Gaithersb., US

Day 1 (July 28, 2011) Morning Session

- **Larry Hudson**, “Precision X-ray Measurements at NIST”
- **Matthias Müller**, “X-ray Fundamental Parameter Work at PTB”
- **Jun Kawai**, “X-ray Fundamental Parameter Work in Japan”
- **Jack Glover**, “X-ray Fundamental Parameter Work in Australia”



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Dissemination of information on the 2011 workshop at NIST, Gaithersb., US

Day 1 (July 28, 2011) Afternoon Session

- Summary of the 3rd Workshop: Marie-Christine Lépy
- Objectives of 4th Workshop: Burkhard Beckhoff
- Update of Reports of Expert Groups: discussions and FP roadmap input
- session devoted to statements of needs & competences from new attendees



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Dissemination of information on the 2011 workshop at NIST, Gaithersb., US**

Day 2 (July 29, 2011) New business

- **Johanna Hoszowska: report on industry-institution collaboration**
- **New business—revision of expert groups** to reflect completion of some tasks and realignment of others as a result of previous workshops.
- **Proposal for realigned groups:** topics, voluntary chairs and members
- **Final session: decisions on follow-up activities** (road map, new groups)

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International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Industrial FP priorities and project activities (“Fribourg group”)**
 - **priorities based on input by industrial manufacturers**
 - **status of industrial FP projects**

*presentation by **Joanna Hoszowska**, Univ. of Fribourg, Switzerland*

European Metrology Research Programme



EC FP7 EMRP IND07 ‘Metrology for the manufacturing of thin films’ (2011 – 2014)

Task 1.5: Determination of atomic fundamental parameters for reference based and reference-free X-ray analysis (**PTB**, CEA/LNE-LNHB). Sep. 2012 – Jan. 2014

Aim: The aim of this task is to **substantially improve the reliability of selected atomic fundamental parameters values of matrix elements** relevant to thin film optoelectronics and relied by X-ray measurements

Description of work: **Selected atomic fundamental parameters, such as optical constants, attenuation coefficients, ionisation cross-sections, fluorescence yields and transition probabilities, will be measured.** Apart from the optimisation of XRS instrumental parameters for thin-film-stacks, the **reduction of the relative uncertainties of relevant fundamental parameters of selected elements of main interest (Cu, In, Ga, S, Se, Cd, Zn, and Mo)** will contribute to the reliability and uncertainty budget of both reference-based and reference-free analytical techniques.



International initiative on x-ray fundamental parameters follow-up workshops and events 2012 to 2014

Recent and current activities:

| | |
|--------------------------------------|------------------|
| 1 st workshop Paris, | Oct. 2008 |
| 2 nd workshop Berlin, | May 2009 |
| Session at EXRS conf. | Jun. 2010 |
| 3 rd workshop Paris, | Oct. 2010 |
| 4 th workshop Gaithersb., | July 2011 |
| Session at EXRS conf. | Jun. 2012 |

Scheduled future activities:

| | |
|---------------------------------|-----------------------|
| Session at DXC conf., USA | Aug. 2012 |
| 5 th workshop Berlin | Feb./Mar. 2013 |
| Event w. TXRF2013, Japan | Sept. 2013 |
| 6 th workshop Paris | Feb./Mar. 2014 |



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Implementation of new expert group structure**
 1. **Project management and fund raising**
 2. **New experimental determinations and methodology**
 3. **Theory & codes – challenges: competent use and update of parameters**
 4. **Integration of new experimental as well as theoretical parameters into critically evaluated compilations**
 5. **Establishment of a common data base accessible to the public**



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Meeting of new expert groups in room MOE58 (max. 20 persons):**
 - **Theory & codes – challenges: competent use and update of parameters**
Monday 16.30 h
 - **New experimental determinations and methodology** **Tuesday 15.40 h**
 - **Integration of new experimental as well as theoretical parameters into critically evaluated compilations** **Thursday 12.30 h**
 - **Establishment of a common data base accessible to the public** **Fr. 10:00 h**
 - **Project management and fund raising** **Friday 10.45 h**



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Meeting of new expert group 3 in room MOE58 (max. 20 persons):
 - Theory & codes – challenges: competent use and update of parameters
- **Monday 16.30 h**
- **participants:** J. Kawai, A. Karydas, St. Fazinić, J. P. Santos, M.-Ch. Lépy, J. Kessler, *and at NIST or DXC2012:* **P. Indelicato, T. Elam, Z. Chen**
- **presentation:** **J. P. Santos**
- **objectives:** setting up a **work agenda**, dissemination to new members



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Meeting of new expert group 2 in room MOE58 (max. 20 persons):**
 - **New experimental determinations and methodology**
Tuesday 15.40 h
 - **participants:** **M.-Ch. Lépy**, J.-Cl. Dousse, St. Gales, J. Hoszowska, M. Kolbe, J. Kessler, M. Krämer, Y. Ménesguen, M. Müller, B. Beckhoff, M. Rodrigues,...
and at NIST or DXC2012: **T. Jach**, Z. Chen, J. Gillaspay, P. Indelicato, J. Sieber, V. Samson, D. Sokaras
 - **objectives:** setting up a **work agenda**, dissemination to new members



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Meeting of new expert group 4 in room MOE58 (max. 20 persons):
 - Integration of new experimental as well as theoretical parameters into critically evaluated compilations **Thursday 12.30 h**
 - participants: J. Kawai, M.-M. Bé, J.E. Fernandez, St. Gales, J.-Cl. Dousse, J. Hoszowska, M. Krämer, T. Papp, *and at NIST or DXC2012:* Z. Chen, J. Glover, Y. Kataoka, V. Kolbytchak, V. Samson
 - objectives: setting up a work agenda, dissemination to new members



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- Meeting of new expert group 5 in room MOE58 (max. 20 persons):
 - Establishment of a common data base accessible to the public
- **Friday 10.00 h**
- **participants:** M. Mantler, M.-M. Bé, B. Beckhoff, J.-Cl. Dousse, J. Hoszowska, M. Krämer, *and at NIST or DXC2012:* B. Cross, J. Sieber
- **objectives:** setting up a **work agenda**, dissemination to new members



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Meeting of new expert group 1 in room MOE58 (max. 20 persons):**
 - **Project management and fund raising**
Friday 10.45 h (just after group 5 meeting)
 - **participants: J. Hoszowska, B. Beckhoff, J.-Cl. Dousse, M.-Ch. Lépy, Y. Ménesguen, M. Müller, ...**
and at NIST or DXC2012: B. Cross, S. Fess, T. Jach, A. Schwartz
 - **objectives: setting up a work agenda, dissemination to new members**



International initiative on x-ray fundamental parameters

Objectives of the EXRS2012 event

- **Meeting of new expert groups in room MOE58 (max. 20 persons):**
 - **Theory & codes – challenges: competent use and update of parameters**
Monday 16.30 h
 - **New experimental determinations and methodology** **Tuesday 15.40 h**
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